

Notice of References Cited	Application/Control No. 09/516,670	Applicant(s)/Patent Under Reexamination SEINO ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,953,058 ✓	09-1999	Hanagata, Takashi	348/223.1
	B	US-6,262,779 ✓	07-2001	Sugiyama et al.	348/704
	C	US-5,767,900 ✓	06-1998	Tanji et al.	348/253
	D	US-6,628,330 ✓	09-2003	Lin, Tao	348/252
	E	US-6,433,836 ✓	08-2002	Suzuki et al.	348/625
	F	US-5,418,574 ✓	05-1995	Miyabata et al.	348/625
	G	US-6,441,866 ✓	08-2002	Chen et al.	348/606
	H	US-6,404,936 ✓	06-2002	Katayama et al.	382/283
	I	US-6,377,313 ✓	04-2002	Yang et al.	348/630
	J	US-6,233,022 ✓	05-2001	Weston et al.	348/625
	K	US-3,980,819 ✓	09-1976	Schwartz, James W.	348/625
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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